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Application No.	10053106	Prepared by	ewc	Tracking Number	05873169
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a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449			
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b			
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract			
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs			
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other			

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Substitute Form PTO-1449 U.S. Department (a) Commerce (Modified) Patent and Trademark Office		Attorney's Docket No. Application No. 09712-132001 10/053,106		
	closure Statement	Applicant Peter de Groot et al.		
(Use several sheets if necessary) (37 CFR §1.96(b))		Filing Date November 2, 2001	Group Art Unit	

				U.S. Pate	ent Documents			
	Examiner Divitial	Desig. ID	Patent Number	issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	4.1	AA	6,195,168 B1	02/2001	De Lega at al.	356	497	
8	4 2002 C	AB	5,398,113	03/1995	de Groot	356	360	
	Ed.	AC						

	Foreign	n Patent Doo	uments or Pu	blished Foreign	Patent /	Application	18	
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AD							
	AE							
	AF							
	AG							
	AH							

Examiner	Desig.	
initial	ID	Document
	ΑĬ	P. de Groot and Leslie Deck, "Surface profiling by analysis of white-light interferograms in the spatial frequency domain," J. Mod. Opt. 42(2), 389-401 (1995).
	AJ	T. Dresel, G. Hausler and H. Venzke, "Three-dimensional sensing of rough surfaces by coherence radar," Appl. Opt. 31(7), 919-925 (1992).
	AK	Gordon S. Kino and Stanley S. C. Chim, "Mirau correlation microscope," Appl. Opt. <u>29</u> (26) 3775-3783 (1990).
	AL	A. Harasaki and J. C. Wyant, "Fringe modulation skewing effect in white-light vertical scanning interferometry," Appl. Opt. 39(13), 2101-2106 (2000).
	AM	L. Deck and P. de Groot, "High-speed non-contact profiler based on scanning white light interferometry," Appl. Opt. 33(31), 7334-7338 (November 1, 1994).

Examiner Signature	Deta Considered
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	Substitute Disclosure Form (PTO-1449)